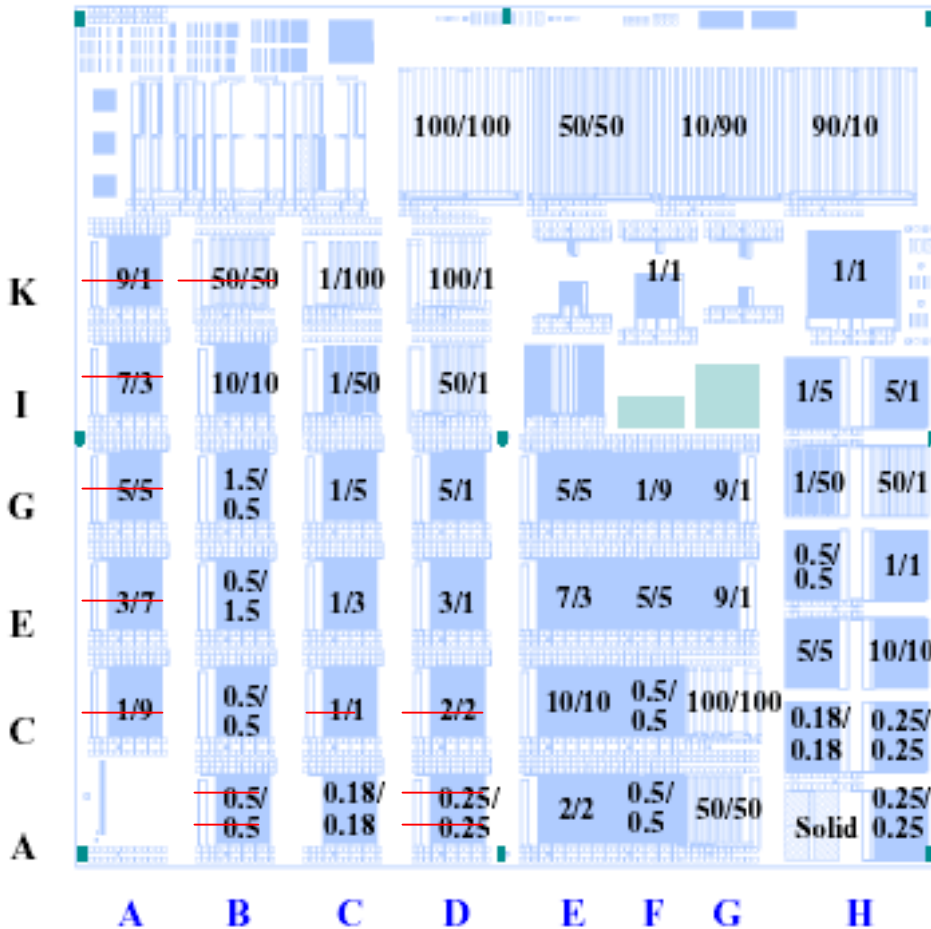
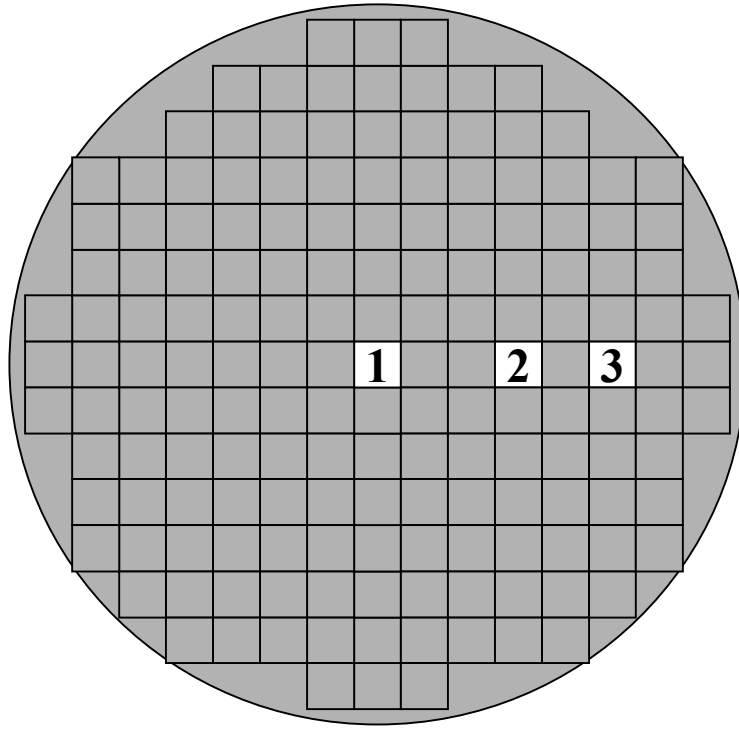


Standard Scan Sampling Plan

(Type: SKW 6-3 Cu/TEOS, 300mm, 3 dies/wafer, 10 scans/die)



Advanced Scan Sampling Plan

(Type:SKW 6-3 Cu/TEOS, 300mm, 3 dies/wafer, 10 scans/die)

